

N-Channel 40 V (D-S) MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A) ^{a, e}	Q _g (Typ.)	
40	0.0058 at V _{GS} = 10 V	50	35 nC	
40	0.0068 at V _{GS} = 4.5 V	25	33 110	

FEATURES

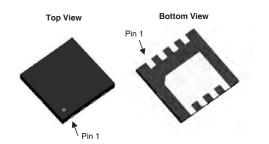
- DT-Trench Power MOSFET
- 100 % R_a and UIS Tested

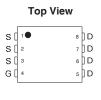


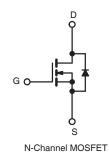
APPLICATIONS

- · Notebook PC Core
- VRM/POL

DFN 3x3 EP







ABSOLUTE MAXIMUM RATINGS (T _A = 25 °C, unless otherwise noted)					
Parameter	Symbol	Limit	Unit		
Drain-Source Voltage		V _{DS}	40	V	
Gate-Source Voltage		V _{GS}	± 20	'	
	T _C = 25 °C		50 ^{a, e}		
Continuous Drain Current (T _{.I} = 175 °C)	T _C = 70 °C] ₋ [42 ^e		
Continuous Drain Current (1) = 175 C)	T _A = 25 °C	l _D	18 ^{b, c}	A	
	T _A = 70 °C	1 [11 ^{b, c}	A	
Pulsed Drain Current		I _{DM}	200		
Avalanche Current Pulse		I _{AS}	48		
Single Pulse Avalanche Energy L = 0.1 mH		E _{AS}	121	mJ	
Continuous Source-Drain Diode Current	T _C = 25 °C	I _S	50 ^{a, e}	А	
Continuous Source-Diam Diode Current	T _A = 25 °C	'S	21 ^{b, c}	A	
	T _C = 25 °C		80	W	
Maximum Power Dissipation	T _C = 70 °C	P _D	52		
	T _A = 25 °C] 'D	5.9 ^{b, c}		
	T _A = 70 °C	1 [3.8 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 175	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	50	55	°C/W	
Maximum Junction-to-Case	Steady State	R _{thJC}	21	26	C/ VV	

- a. Based on T_C = 25 °C.
 b. Surface mounted on 1" x 1" FR4 board.
 c. t = 10 s.
 d. Maximum under steady state conditions is 90 °C/W.
- e. Calculated based on maximum junction temperature. Package limitation current is 10 A.



Parameter	Symbol	Test Conditions	Min .	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	40			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		35		m\//0C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	ι _D = 230 μΑ		- 5.5		mV/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1		3	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zoro Coto Voltogo Drain Current	la a a	V _{DS} = 32 V, V _{GS} = 0 V			1		
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 32 V, V _{GS} = 0 V, T _J = 55 °C			10	μA	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	50			Α	
D 1 0 0 0 1 1 1 1 1	D.	V _{GS} = 10 V, I _D = 20 A		0.0058	0.007	7	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 15 \text{ A}$		0.0068	0.0082	Ω	
Forward Transconductance ^a	g _{fs}	$V_{DS} = 32V, I_{D} = 10 A$		80		S	
Dynamic ^b							
Input Capacitance	C _{iss}			3340			
Output Capacitance	C _{oss}	$V_{DS} = 32 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		369		pF	
Reverse Transfer Capacitance	C _{rss}			50		1	
T. 10 1 0	Qg	$V_{DS} = 32 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$		35		nC	
Total Gate Charge				15			
Gate-Source Charge	Q _{gs}	$V_{DS} = 32 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 15 \text{ A}$		7			
Gate-Drain Charge	Q _{gd}			4			
Gate Resistance	R_g	f = 1 MHz		1.5	2.3	Ω	
Turn-On Delay Time	t _{d(on)}			16	22		
Rise Time	t _r	V_{DD} = 32 V, R_L = 0.555 Ω		11	19		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 20$ A, $V_{GEN} = 10$ V, $R_g = 1$ Ω		32	45		
Fall Time	t _f			8	15	no	
Turn-On Delay Time	t _{d(on)}			38	53	ns	
Rise Time	t _r	V_{DD} = 32 V, R_L = 0.625 Ω		60	70	-	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 15 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		25	45		
Fall Time	t _f			8	12		
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	$T_C = 25 ^{\circ}C$			50	٨	
Pulse Diode Forward Current ^a	I _{SM}				200	Α	
Body Diode Voltage	V _{SD}	I _S = 12 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			50	72	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	L_ = 10 A di/dt = 100 A/up T = 25 °C		65	99	nC	
Reverse Recovery Fall Time	ta	$I_F = 10 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		24		,	
Reverse Recovery Rise Time	t _b	7		20		ns	

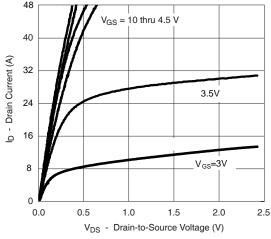
Notes:

- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

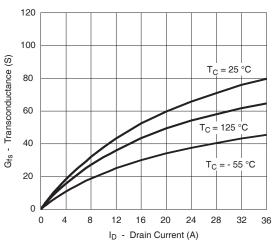
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



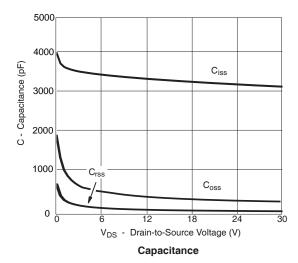
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

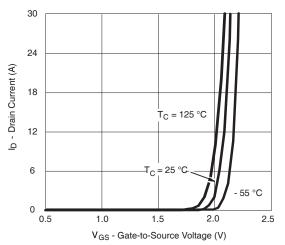


Output Characteristics

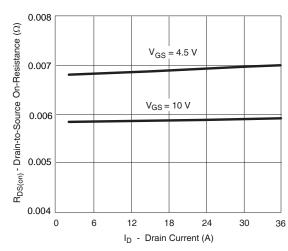


Transconductance

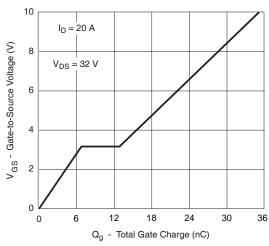




Transfer Characteristics

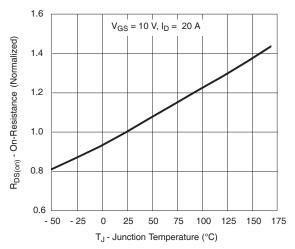


R_{DS(on)} vs. Drain Current

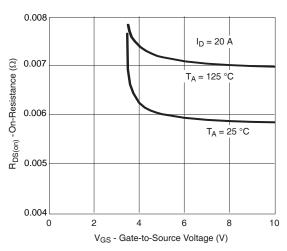


Gate Charge

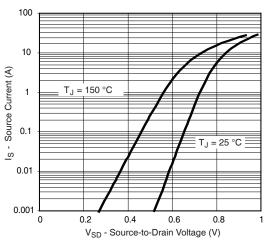
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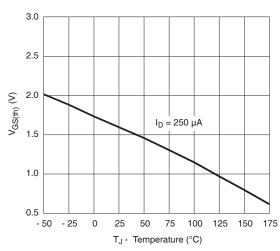
On-Resistance vs. Junction Temperature



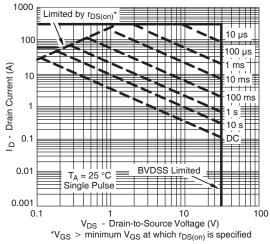
 $R_{DS(on)}$ vs. V_{GS} vs. Temperature



Forward Diode Voltage vs. Temperature



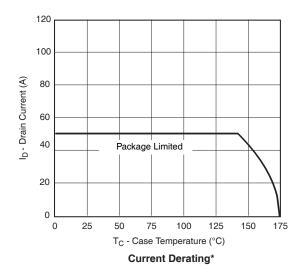
Threshold Voltage

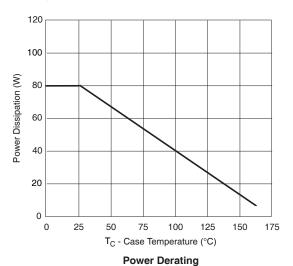


Safe Operating Area, Junction-to-Ambient

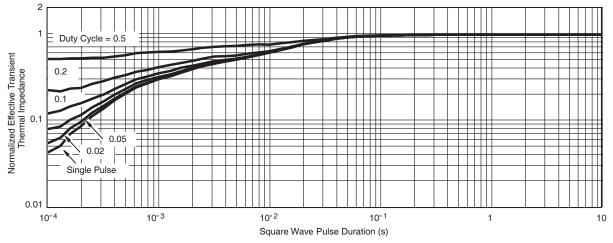


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)





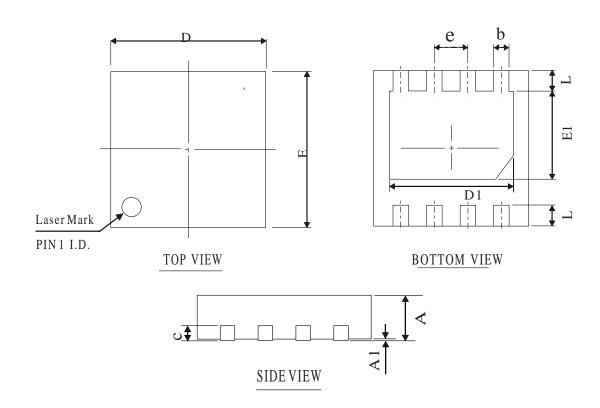
* The power dissipation P_D is based on $T_{J(max)} = 175$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



Normalized Thermal Transient Impedance, Junction-to-Case



DFN3*3-8L PACKAGE OUTLINE



COMMON DIMENSIONS (UNITS OF MEASURE=mm)

SYMBOL	MIN	NOM	MAX
Α	0. 60	0.75	0. 90
A1	0. 00	0.02	0. 08
b	0. 20	0.30	0.45
D	2. 85	3.00	3. 15
Е	2. 85	3.00	3. 15
D1	2. 10	2.40	2.70
E1	1.50	1.70	2.00
L	0. 20	0.40	0.60
С	0. 203 REF		
e	0. 65 BSC		

OTHER DIMENSIONS

A	0. 50	0.55	0.60
A	0.40	0.45	0.50





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